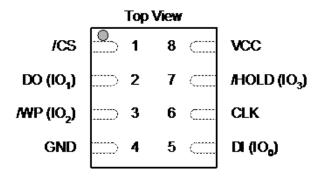


### New Architecture for Code-Shadowing Applications

Dual-buffer SPI-NAND Arch providing SPI-NOR compatibility

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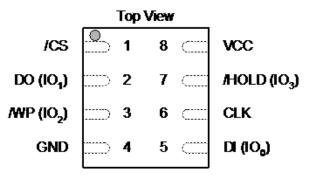




#### Key features of New Architecture (Dual-buffer SPI-NAND):

- Package and pin-out compatibility with SPI-NOR (both with 8-pin foot-print)
- Read command and clocking compatibility with SPI-NOR Flash
  - High speed continuous/<u>sequential read</u> across Page and Block boundaries
- > New Arch compatible with SPI-NOR Flash in "code shadowing" applications
  - SPI-NOR not likely to be displaced in <u>XIP</u> applications for fast <u>random access</u>
- Fully integrated on-chip solution for high speed continuous/sequential read :
  - Dual-buffer Arch provides gapless interleaved read
  - On-chip ECC (error-correcting code)
  - On-chip LUT (look-up table) for BBM (bad block management)
  - Eliminates need for ext. controller chip for providing ECC and LUT (for BBM)





#### Major benefits of new SPI-NAND Arch:

• Highly cost effective solution for "code shadowing" applications

- NAND cell size ~<u>4.5F2</u> much smaller compared to NOR cell size ~<u>12F2</u>
- NOR floating gate technology reaching scaling limit ~45nm, whereas NAND has scaling path down to 1Xnm
  - NOR has one CO (contact) per cell, whereas NAND has one CO per string
    •String may be 32, 64, or 128 cells
  - Programming by CHE (channel hot electron) in NOR, but tunneling in NAND
    •Cell channel length has scaling limit due to CHE
- Large SPI-NAND densities in 8-pin package, e.g. 1Gb on 4X nm and 2Gb on 3X nm in 6x8 WSON package
  - In the SPI-NOR Flash, 128Mb/256Mb are largest densities to fit 6x8 WSON
- SPI-NAND is attractive alternative in code-shadowing for higher densities
  - SPI-NOR densities < 256Mb are already able to offer small footprint (e.g. 6X8 WSON)

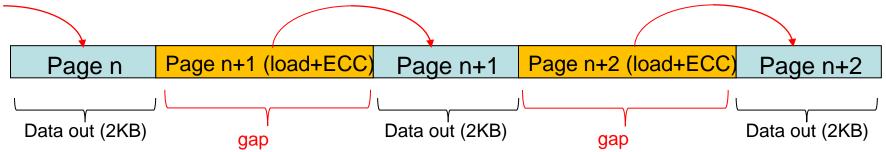
<u>Note</u>: NOR offers fast random access because of higher cell current, and NOR doesn't require BBM



#### Code shadowing: Legacy Arch vs New Arch

(comparing both Single Array/Plane Arch)

#### 1. Legacy Architecture: read with gaps



#### 2. <u>New Dual-Buffer Arch</u>: continuous/sequential read without gaps

Page n	Page n+1	Page n+2	Page n+3	Page n+4	Page n+5
Data out (2KB)					

1. Legacy Arch suffers large gaps (e.g. 50us+) between reading out data from consecutive pages

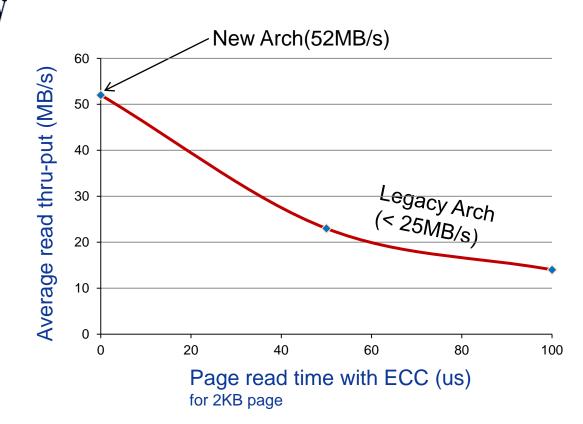
• Gaps due to Page read : load data from NAND Array to Page Buffer plus ECC computation

2. <u>New Arch provides "gapless" continuous read across Page and Block boundaries</u>

• Ideal for Code Shadowing applications when large amount of data is sequentially read out

Average read thru-put (MB/s) vs. Page Read time with ECC

for Quad (4-bit I/O) operation and 104MHZ Clock Freq



Legacy Arch: Average read thru-put (< 25MB/s) much slower than 52MB/s in New Arch</li>

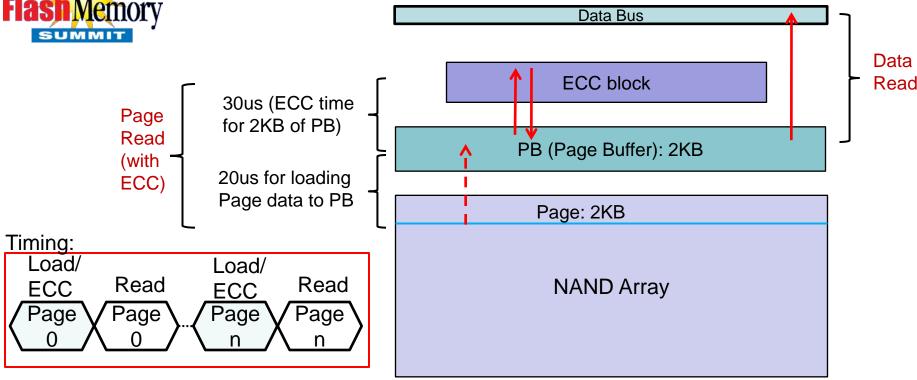
• There may be 50us+ gaps (Page read time with ECC), before each 2KB data read out

• <u>New Arch</u>: Average read thru-put 52MB/s is exactly half of the 104MHZ Clock Freq (Quad I/O)

• Page read time with ECC time is completely hidden from the read thru-put



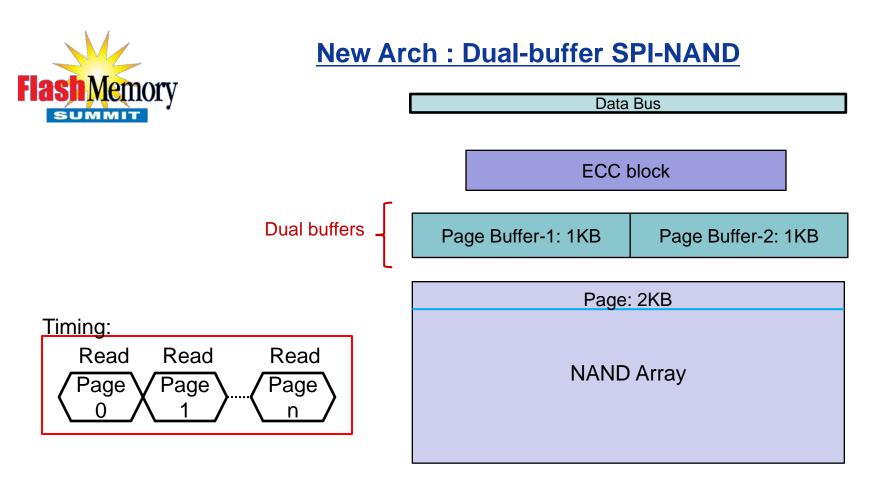
#### Legacy Single Array/Plane NAND Arch



#### Two common NAND operations:

- a. Page read operation : 20uS (load time) + 30us (ECC time) ~ 50us
  - Page read time in NAND products without on-chip ECC ~ 20us
- b. Data read operation : read out 2KB page data from PB through data bus
- Next Page read incurs 50us wait again → big overhead in Code Shadowing applications !

Flash Memory Data read for next page can only start after completion of next page read operation Santa Clara, CA

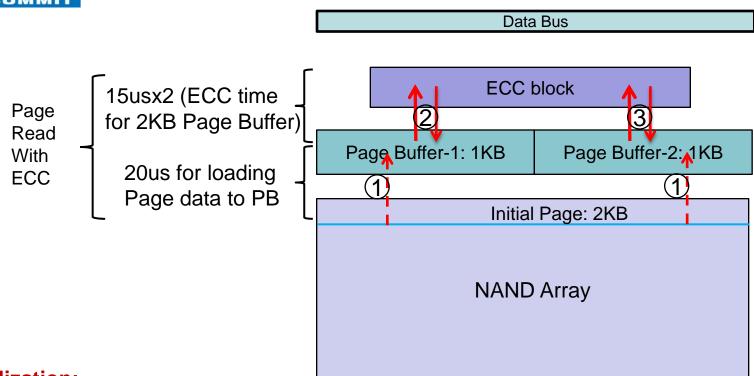


- New Arch uses Dual-buffers, while retaining die size benefit offered by Single Array/Plane
- "<u>Continuous read</u>" operation offered with no gaps at page and block boundaries !
  - Continuous read is achieved by interleaved read from dual Page Buffers
  - Page read time (load data to PB + ECC) is completely hidden from the read thru-put
- > Continuous read in new Arch comprises 2 steps : (i) Initialization, and (ii) Interleaved read



#### **Continuous read operation in new Arch:**

1<sup>st</sup> step : "Initialization"



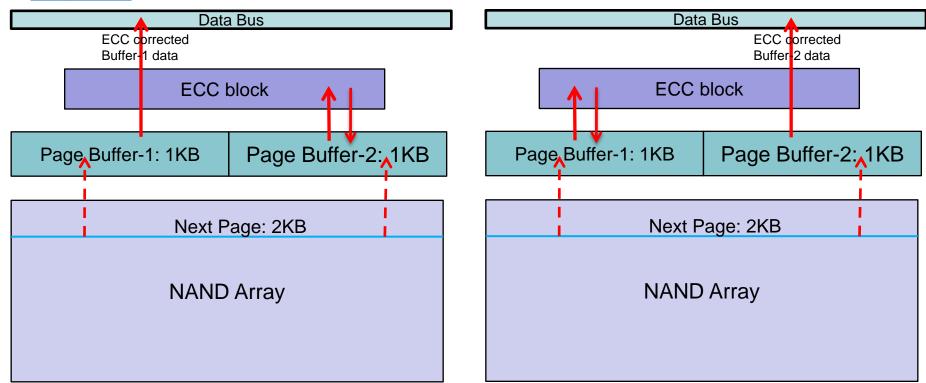
#### Initialization:

- Above operation 1+2+3 (50us, i.e. 20us+15us+15us) is one-time latency prior to starting of each continuous read operation (note: step 3 during initialization is optional)
- >Initialization can be hidden in P/U sequence, with Page-0 read (including ECC) during power-up
  - Many code-shadow applications starting download from Page-0/byte-0 may incur no latency
- Appls with code-shadow starting from other than Page-0 may incur initial 50us page read latency

# FlashMemory

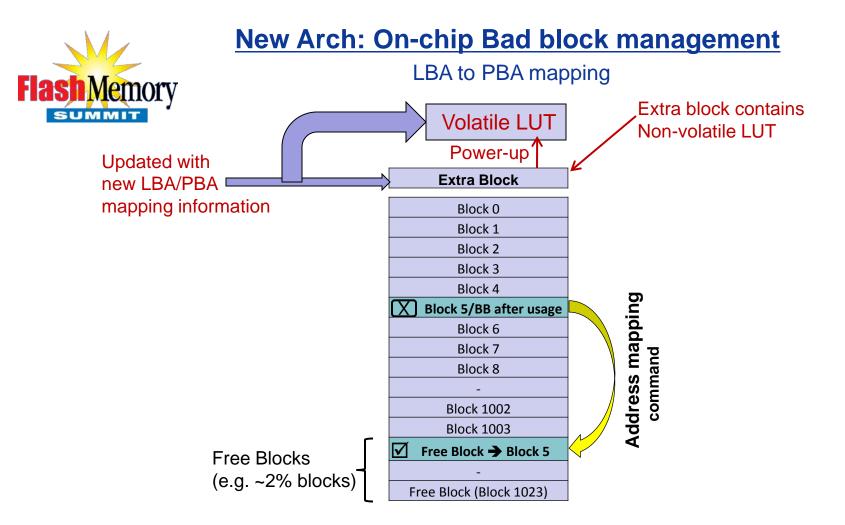
#### Continuous read operation in new Arch:

2<sup>nd</sup> step : repetitive "Interleaved read"



#### Interleaved read:

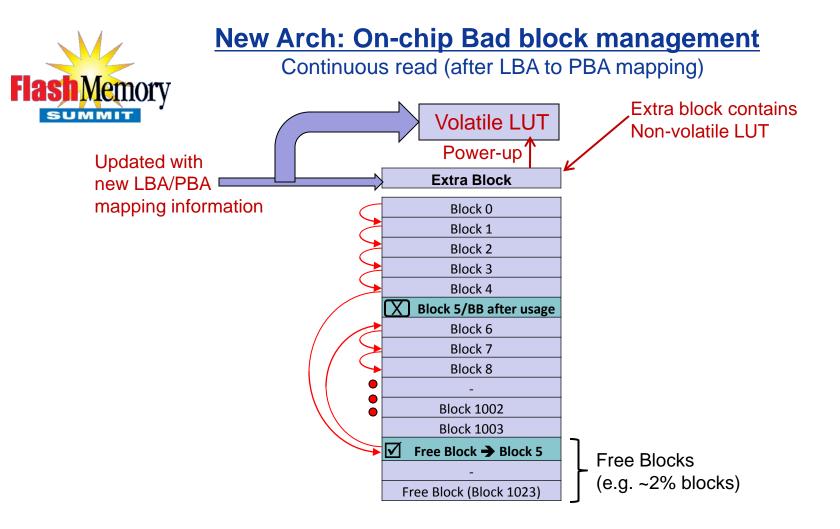
- Buffer-1 data is outputted while ECC is carried out on Buffer-2 data, and vice versa
  - Data from next page can transfer concurrently to PB, since PB has 2-levels (L1/L2 latches)
- Pipelined operation with 3 concurrent steps: Data out from PB, ECC calculation, load data to PB
- Data read out continuously without gaps, by alternately reading from Buffer-1/Buffer-2 Flash Memory Summit 2013 Santa Clara, CA



• User may issue "address mapping" command, e.g. on Erase/Verify or Program/Verify fail

- Along with address mapping command, user provides LBA to PBA mapping information
- Mapping information (LBA to PBA) saved in both non-volatile and volatile LUT
- On each P/U (power-up), mapping information from non-volatile LUT read into volatile LUT

#### > Need for ext. controller chip with LUT (for LBA/PBA mapping info.) has been eliminated



- Red arrows show continuous read traversing from block-to-block
  - Bad blk skipped and read redirected to good replacement blk (using on-chip LUT for BBM)

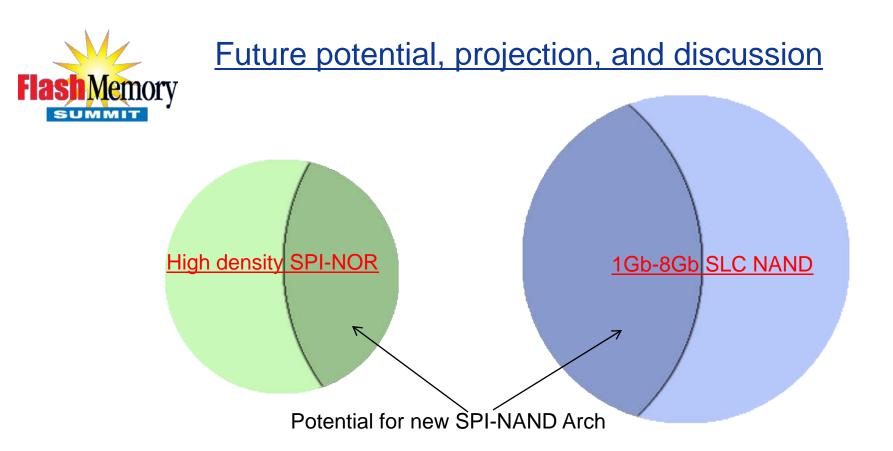
#### Fast continuous read across block boundaries not possible with LUT in ext. controller

- On-chip volatile LUT with fast access facilitates high speed cont. read in case of bad block
- On each P/U (power-up), mapping information from non-volatile LUT read into volatile LUT Flash Memory Summit 2013 Santa Clara, CA



#### **Summary**:

- A new Arch has been described for Code-Shadowing applications
  - New dual-buffer Arch provides Interleaved continuous/sequential read
  - Small die size due to Single Array/Plane key to fit 1Gb/2Gb in 8-pin pkg.
- Data is read out continuously without gaps at Page and Block boundaries
  - Continuous read operation at 104MHZ and even at 133MHZ is feasible
- Continuous reading out of data is compatible with SPI-NOR Flash
  - Package, pin-out, command, and clocking compatibility with SPI-NOR
- Unlike traditional NAND, no need of ext. cont. chip for ECC and LUT (BBM)
  - Fully integrated on-chip solution has been proposed
- Building blocks of New Arch (dual buffer, on-chip LUT for BBM) have been described to achieve high speed continuous/sequential read in code-shadowing applications



- New SPI-NAND Arch will overlap with 1Gb-8Gb SLC NAND, in addition to high density SPI-NOR
- Read thru-put (Quad, sequential) better than SLC NAND (8/16 pin), and 8-pin foot-print attractive
- SPI-NOR introduced in 90's evolved to replaced many Parallel-Flash appls due to 8-pin foot-print
  - Evolution was accelerated due to higher thru-put offered by multi I/O SPI, e.g. Quad I/O
- Similar trend could take place in migration from 1Gb-8Gb SLC NAND to new SPI-NAND Arch



# **Thanks**